L Number	Hits	Search Text	DB	Time stamp
1	4607	((257/48) or (438/18) or (324/158.1) or (324/133) or (324/501)).CCLS.	USPAT; US-PGPUB	2004/10/13 17:00
2	1	(((257/48) or (438/18) or (324/158.1) or (324/133) or (324/501)).CCLS.) and (laser adj voltage adj probe lvp) near6 gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/13 17:01
3	317	(((257/48) or (438/18) or (324/158.1) or (324/133) or (324/501)).CCLS.) and (test testing non-invasive laser adj voltage adj probe lvp) near6 gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/13 17:02
4	345	(((257/48) or (438/18) or (324/158.1) or (324/133) or (324/501)).CCLS.) and (test testing non-invasive laser adj voltage adj probe lvp) near6 gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/13 17:02
-	0	(324/158).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/13 11:34
-	3960	324/158$3.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/28 21:17
-	3960	324/158.$3.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/28 21:17
-	0	lvp.ti,ab. and 257/$6.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/28 21:20
-	2	lvp.ti,ab. and probe	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/28 21:20
-	24	lvp.ti,ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/28 21:21
-	4741	((257/48).CCLS.) or 324/158.$3.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 12:55
-	7	(((257/48).CCLS.) or 324/158.$3.ccls.) and (mosfet or cmosfet or nmosfet or pmosfet or cmos or nmos or pmos) and (test or testing or diagnostic) near12 laser	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/05 15:36
-	8	(((257/48).CCLS.) or 324/158.$3.ccls.) and (mosfet or cmosfet or nmosfet or pmosfet or cmos or nmos or pmos) and (test or testing or diagnostic) near12 (optic or optical)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 13:01
-	2	(((257/48).CCLS.) or 324/158.$3.ccls.) and (mosfet or cmosfet or nmosfet or pmosfet or cmos or nmos or pmos) and (test or testing or diagnostic) near12 (pn adj junction)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 13:08

–		26	(((257/48).CCLS.) or 324/158.$3.ccls.) and (mosfet or cmosfet or nmosfet or pmosfet or cmos or nmos or pmos) and (test or testing or diagnostic) and (pn adj junction or p-n adj junction or pn-junction)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 13:15
–		3	laser near12 diagnostic near12 (np adj junction or n-p junction or np-junction)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 13:17
–		16	laser near12 (test or testing) near12 (np adj junction or n-p junction or np-junction)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 17:33
–		11	tsang.in. and kash.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 17:40
–		327	(324/501).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 17:41
–		801	(257/48).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 18:10
–		3960	324/158.$4.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 18:15
–		8	324/158.$4.ccls. and (pn adj junction or p-n adj junction or pn-junction or p-n-junction) and (laser or optical)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/05 19:09
–		280	(438/18).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/06/29 18:17
–		913	(257/48).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 16:34
–		91	((257/48).CCLS.) and test$3 near6 gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 16:36
–		22	((257/48).CCLS.) and test$3 near6 gate and (cmos or cmosfet)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 16:38
–		3	((257/48).CCLS.) and test$3 near6 gate and (cmos or cmosfet) and (laser or irradiat$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:15
–		0	((257/48).CCLS.) and optical near3 prob$3 near6 gate and (cmos or cmosfet) and (laser or irradiat$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:16

–		0	((257/48).CCLS.) and optical near3 prob$3 near6 gate and (cmos or cmosfet)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:17
–		0	((257/48).CCLS.) and (laser or radiat$3 or irradiat$3) near6 prob$3 near6 gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:18
–		33	((257/48).CCLS.) and prob$3 near6 gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:19
–		31	(((257/48).CCLS.) and prob$3 near6 gate) not (((257/48).CCLS.) and test$3 near6 gate and (cmos or cmosfet))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:20
–		24	((257/48).CCLS.) and laser near6 (test$3 or prob$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:21
–		38	((257/48).CCLS.) and (optical or laser) near6 (test$3 or prob$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:26
–		1	((257/48).CCLS.) and (lvp or laser adj voltage adj probe)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:27
–		33	(lvp or laser adj voltage adj probe) and (mos or cmos or mosfet or cmosfet)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:28
–		3	(lvp or laser adj voltage adj probe) and (mos or cmos or mosfet or cmosfet) and (test$3 or prob$3) near6 gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 17:29
–		44	(lvp or laser adj voltage adj probing).ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/03 20:39
–		0	(back-side or backside or back adj side) near3 (lvp or laser adj voltage adj (probing or probe))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 09:54
–		1	(back-side or backside or back adj side) near12 (lvp or laser adj voltage adj (probing or probe))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 10:05
–		1	"6428718".PN.	USPAT	2003/03/04 09:57
–		1	"6403439".PN.	USPAT	2003/03/04 10:03
–		10	(lvp or laser adj voltage adj (probing or probe)) and (cmos or cmosfet)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 10:59
–		1	"6331453".PN.	USPAT	2003/03/04 10:09

–	1	non-invasive near3 optical near12 (cmos or cmosfet)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 10:15
–	13	reverse adj voltage near6 (cmos or cmosfet)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 11:01
–	1	reverse adj voltage near6 (cmos or cmosfet) and (laser adj voltage adj (probing or probe))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 11:02
–	11	reverse adj voltage near6 (cmos or cmosfet) and (test$3 or prob$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 11:06
–	2	reverse adj voltage near6 (cmos or cmosfet) and (test$3 or probe or probing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 12:00
–	2	("6084267").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/04 12:00
–	11	(((257/48).CCLS.) or 324/158.$3.ccls.) and (mosfet or cmosfet or nmosfet or pmosfet or cmos or nmos or pmos) and (test or testing or diagnostic) near12 laser	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/05 10:57
–	1	("6197109").PN.	USPAT	2003/08/05 15:37
–	3018	324/158$3.ccls. 257/48.ccls. 438/18.ccls.	USPAT; US-PGPUB	2003/08/05 19:09
–	77	(324/158$3.ccls. 257/48.ccls. 438/18.ccls.) and (lvp laser adj voltage adj probe laser-voltage-probe laser adj voltage-probe (laser near12 (test$3 diagnostic$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/05 19:12
–	100	yoshida.in. and eiji.in.	USPAT; US-PGPUB	2003/08/06 08:42
–	1	yoshida.in. and eiji.in. and transistor.clm. and laser.clm.	USPAT; US-PGPUB	2003/08/06 08:43
–	6	yoshida.in. and eiji.in. and semiconductor and gate and laser	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:14
–	2	("6137295").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:15
–	6	392925.ap.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:27
–	5806	((324/158.1) or (324/501) or (257/48)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:27
–	10	(((324/158.1) or (324/501) or (257/48)).CCLS.) and laser near20 junction	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:41

-	398	(438/18).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:41
-	2	((438/18).CCLS.) and laser near20 junction	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:41
-	6	lvp.ti,ab,clm. and probe	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 15:56
-	437	cmos.ti,ab,clm. and drain near3 (connect connected) near3 source and common near2 (source drain)	USPAT	2003/10/19 18:18
-	109	cmos.ti,ab,clm. and drain near3 (connect connected) near3 source and common near2 (source drain) and 257/$9.ccls.	USPAT	2003/10/19 18:19
-	299	nmos near12 pmos and common adj (source drain) and 257/$9.ccls.	USPAT; EPO; JPO	2003/10/19 19:45
-	0	dillinger.in. and protection and gate	USPAT; EPO; JPO; DERWENT	2003/10/19 19:48
-	74	latchup and testing and (257/$9.ccls. 438/$9.ccls.)	USPAT; EPO; JPO; DERWENT	2003/10/19 19:53
-	9	(latchup latch-up) near12 testing and (257/$9.ccls. 438/$9.ccls.)	USPAT; EPO; JPO; DERWENT	2003/10/19 20:10
-	1012	(257/48).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 20:11
-	1012	(257/48).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 20:11
-	542	(257/48).CCLS.	USPAT	2003/10/19 20:13
-	27	((257/48).CCLS.) and pmos and nmos	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/19 20:13
-	3	931104.ap.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/13 17:00